## IN THE CLAIMS:

Cancel claim 24.

Claims 23, 25, and 27 have been amended herein. All of the pending claims 23 and 25 through 30 are presented below. This listing of claims will replace all prior versions and listings of claims in the application. Please enter these claims as amended.

## **Listing of Claims:**

- 1-22. (Canceled)
- 23. (Currently Amended) A pixel, comprising: a single-layered substrate further comprising:
  - a generally planar surface comprising semiconductive material having an impurity concentration the greatest at the generally planar surface;
  - at least one protuberance formed from said generally planar surface into the substrate, the at least one protuberance having an apex substantially formed from a portion of said generally planar surface; and
  - an impurity offset from the apex of the at least one protuberance formed from a portion of said generally planar surface and within said protuberance, said impurity within said protuberance having a concentration increasing decreasing concurrently with a distance from the apex substantially formed from a portion of said generally planar surface.
  - 24. (Canceled)
- 25. (Currently Amended) A field emission display, comprising:
   a remaining portion of a single-layered substrate, the remaining portion being an uncontaminated single-layered substrate that is at least semiconductive formed from a single-layered substrate having an upper surface, the single-layered substrate having an impurity

- concentration greatest at the upper surface while decreasing with a distance from the upper surface; and
- a micro-cathode located in a portion of said substrate formed from the portion of the singlelayered substrate having an impurity concentration greatest at the upper surface thereof, further comprising:
  - a contaminated apex having an impurity concentration substantially the same as a portion of the single-layered substrate at the upper surface thereof; and <a href="mailto:an increasingly">an increasingly a decreasingly</a> contaminated body, the concentration of the impurity <a href="increasing decreasing">increasing decreasing</a> from the contaminated apex.
- 26. (Previously Presented) The field emission display of claim 25, wherein said micro-cathode is integral with said substrate.
- 27. (Currently Amended) A display panel, comprising:

  a substrate comprising semiconductive material formed from a single-layered substrate having an upper surface, the single-layered substrate having an impurity concentration greatest at the upper surface while decreasing with a distance from the upper surface; and an emitter electrode located in a portion of said substrate, further comprising an apex having an impurity concentration substantially the same as a portion of the single-layered substrate at the upper surface thereof, and further having an etch-resistible quality that decreases with depth from said apex.
- 28. (Previously Presented) The display panel in claim 27, wherein said emitter electrode further comprises a base and further has an oxidizable quality that increases with elevation from said base.
- 29. (Previously Presented) The display panel in claim 28, wherein a portion of said substrate that is under said emitter electrode has an etch-resistible quality generally similar to an etch-resistible quality of said base.

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30. (Previously Presented) The display panel in claim 29, wherein said portion has an oxidizable quality generally similar to an oxidizable quality of said base.

31-32. (Canceled)